

Docket No.: 60188-570

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of	:	Customer Number: 20277
Katsuki NAGAHASHI, et al.	:	Confirmation Number: not yet assigned
Serial No.: not yet assigned	:	Group Art Unit: not yet assigned
Filed: August 04, 2003	:	Examiner: not yet assigned
For:		ACCELERATED TEST METHOD FOR FERROELECTRIC MEMORY DEVICE

INFORMATION DISCLOSURE STATEMENT

Mail Stop
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

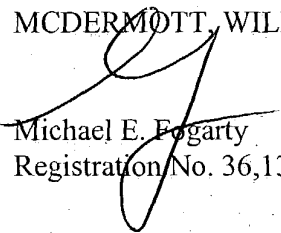
The relevance of each non-English language reference, if any, is discussed in the present specification.

not yet assigned

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

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<p align="center">INFORMATION DISCLOSURE</p> <p align="center">CITATION IN AN</p> <p align="center">APPLICATION</p> <p align="center">(PTO-1449)</p>	<p>ATTY. DOCKET NO.</p> <p>60188-570</p>	<p>SERIAL NO.</p> <p>not yet assigned</p>
	<p>APPLICANT</p> <p>Katsuki NAGAHASHI, et al.</p>	
	<p>FILING DATE</p> <p>August 04, 2003</p>	<p>GROUP</p> <p>not yet assigned</p>

U.S. PATENT DOCUMENTS

[illegible]

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Code - Number - Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No
	A	11-174026 with English abstract	07/02/1999	Fujitsu Ltd.			

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.):

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
	7A	"Polarization Fatigue Characteristics of Sol-Gel Ferroelectric", Takashi Mihara et al., Jpn. J. Appl. Phys, Vol. 33 (1994) pp. 3996-4002, Part 1, No 7A, July 1994

EXAMINER	DATE CONSIDERED
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.